

**Notice of References Cited**

Application/Control No.

10/712,368

Applicant(s)/Patent Under  
Reexamination  
CHANG ET AL.

Examiner

Michelle R. Connelly-Cushwa

MC 8/18/05

Art Unit

2874

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-2004/0120721 A1	06-2004	Wang et al.	398/195
X	B	US-2003/0035617 A1	02-2003	Plourde et al.	385/24
X	C	US-2003/0174743 A1	09-2003	Cliche et al.	372/20
X	D	US-6,560,252 B1	05-2003	Colbourne et al.	372/32
X	E	US-2004/0101319 A1	05-2004	Choi et al.	398/196
X	F	US-6,243,403 B1	06-2001	Broutin et al.	372/32
X	G	US-2003/0138007 A1	07-2003	Lee et al.	372/32
X	H	US-6,122,087 A	09-2000	Nogiwa et al.	398/196
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.